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Application/Control No.	Applicant(s)/Patent under Reexamination	
09/823,272	SHIN ET AL.	
Examiner	Art Unit	
Yubin Huna	2625	

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Class	Subclass	Date	Examiner
382	162,165 168,173 181 190-192	8/30/2005	YH
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Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST Text search (US PG_PUB, USPAT, EPO, JPO, DERWENT, IBM- TDB)	8/29/2005	ΥH
IEEE Xplore	8/29/2005	ΥH
ACM	8/29/2005	ΥH
SPIE	8/29/2005	ΥH